

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/819,434	INUI ET AL.
	Examiner	Art Unit
	Dah-Wei D. Yuan	1745

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
429	120	3/31/2005	DWY
429	149	3/31/2005	DWY
429	152	3/31/2005	DWY